Publications List of Prof. Shen-Li Chen

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Research Fields (Expertise):
- Power Electronics, BCD Process (HV, UHV)
- VLSI Reliability
- ESD/EOS Protection Design
- CMOS Latchup Free Design/Testing
- System EMC/EMS Testing and Troubleshooting

A. Referred Journal papers: (2014~2021)


B. Book Chapter Series: (2014~2021)


C. Referred Conference Papers: (2014~2021)


22. Sheng-Kai Fan, Shen-Li Chen*, Po-Lin Lin, Shi-Zhe Hong, Tien-Yu Lan and Yu-Jie


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D. Patents 專利：(2014~2021)
2. 陳勝利, "半導休結構", 中華人民共和國實用新型專利，證書# CN 4085412 (ZL2014-2-0375327.2), pp. 1~11, 2014.07.08 ~ 2023.07.07
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